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Defense Economic Impact Modeling System (DEIMS). A New Concept in Economic Forecasting for Defense Expenditures.

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The Defense Economic Impact Modeling System (DEIMS) analyzes the economic effect of defense expenditures on the United States economy by using a consistent, reliable framework of economic models and government policy assumptions. Planning information on defense requirements is also provided to private sector firms. The DEIMS allows the Department of Defense to analyze the impact of alternative defense budgets on key industrial sectors, skilled labor categories, and raw material requirements at a level of product disaggregation consistent with the Department of Commerce's four-digit Standard Industrial Classification categories. It combines (1) a macroeconomic model adapted to integrate the impact on key industrial sectors of specific defense production requirements; (2) a producer price modeling system; (3) a 400 sector, commodity-based, input-output and employment model; (4) a 161 category skilled-lab or requirements model; and (5) a 72commodity, quantity-based, strategic materials requirements model. All models are maintained by Data Resources, Inc. DEIMS output display tables are designed to provide forecasts of future defense needs and thus stimulate more active competition among companies. (Sample tables and listings of sectors, skill categories, and strategic materials requirements covered in the model are appended.) (YLB)

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